Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/725,133	LEE ET AL.
Examiner	Art Unit
Wen-Ying P. Chen	2871

	SEARCHED		
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
349 combined with key words search of all databases in EAST	12/28/2005	WPC
review previously cited references	12/29/2005	WPC
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